

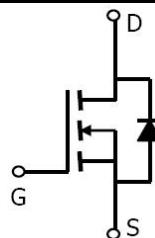
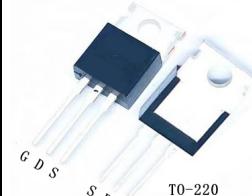
P/N: YZPST-SP13N50KF

**500V N-Channel Power MOSFET****FEATURES**

- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

**APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

**Parameters Summary****VDS:500V ID (at VGS=10V) :13A Rds(on) (at VGS=10V):0.40Ω(Typ.)****Symbol****SP13N50KF****Device Ordering Marking Packing Information**

Ordering Number	Package	Marking	Packing
SP13N50KF	TO-220	SP13N50KF	Tube

**Absolute Maximum Ratings**  $T_C = 25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Value	Unit
		TO-220	
Drain-Source Voltage ( $V_{GS} = 0\text{V}$ )	$V_{DSS}$	500	V
Continuous Drain Current	$I_D$	13	A
Pulsed Drain Current (note1)	$I_{DM}$	52	A
Gate-Source Voltage	$V_{GSS}$	$\pm 30$	V
Single Pulse Avalanche Energy (note2)	$E_{AS}$	550	mJ
Repetitive Avalanche Energy (note1)	$E_{AR}$	65	mJ
Power Dissipation ( $T_C = 25^\circ\text{C}$ )	$P_D$	60	W
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55~+150	°C

*Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.*

**Thermal Resistance**

Parameter	Symbol	Value	Unit
		TO-220	
Thermal Resistance, Junction-to-Case	$R_{thJC}$	2.1	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{thJA}$	100	°C/W

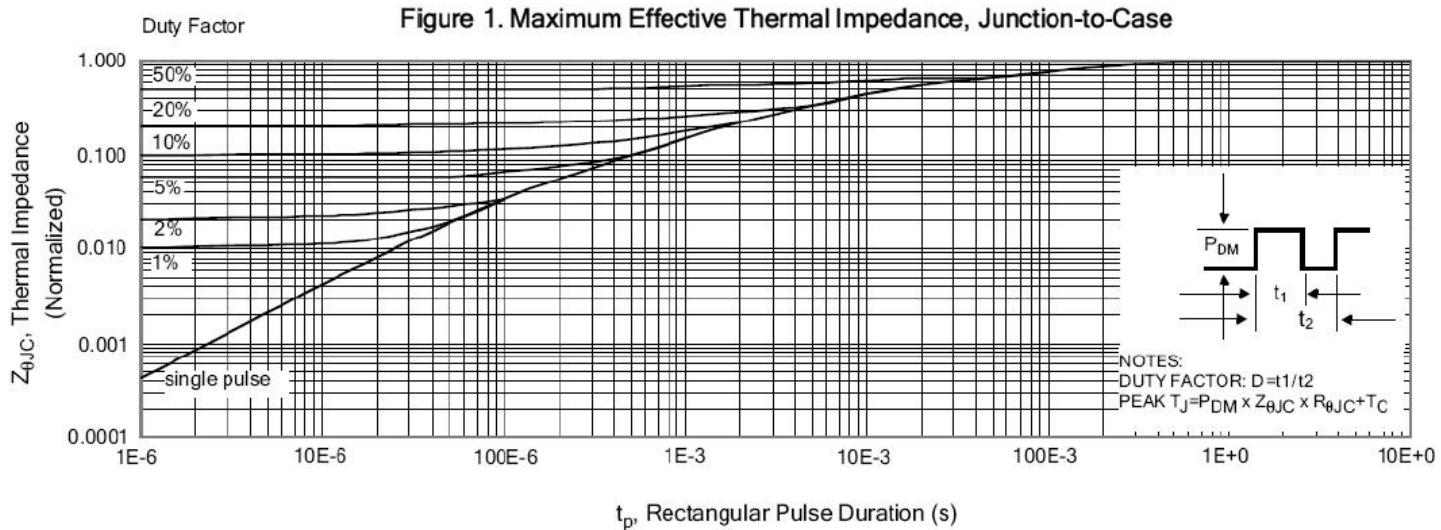
**Specifications**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	500	--	--	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 500\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 25^\circ\text{C}$	--	--	1.0	$\mu\text{A}$
Gate-Source Leakage	$I_{\text{GSS}}$	$V_{\text{GS}} = \pm 30\text{V}$	--	--	$\pm 100$	nA
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$I_{\text{DS}} = 250\mu\text{A}$	2.0	--	4.0	V
Drain-Source On-Resistance (Note3)	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 6.5\text{A}$	--	0.40	0.50	$\Omega$
<b>Dynamic</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1.0\text{MHz}$	--	2100	--	pF
Output Capacitance	$C_{\text{oss}}$		--	23	--	
Reverse Transfer Capacitance	$C_{\text{rss}}$		--	210	--	
Total Gate Charge	$Q_g$	$V_{\text{DD}} = 250\text{V}, I_D = 13\text{A}, V_{\text{GS}} = 10\text{V}$	--	45	--	nC
Gate-Source Charge	$Q_{\text{gs}}$		--	11	--	
Gate-Drain Charge	$Q_{\text{gd}}$		--	18	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 250\text{V}, I_D = 13\text{A}, R_G = 6.1\Omega$	--	14	--	ns
Turn-on Rise Time	$t_r$		--	27	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	45	--	
Turn-off Fall Time	$t_f$		--	36	--	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Body Diode Current	$I_S$	$T_C = 25^\circ\text{C}$	--	--	13	A
Pulsed Diode Forward Current	$I_{\text{SM}}$		--	--	52	
Body Diode Voltage	$V_{\text{SD}}$	$T_J = 25^\circ\text{C}, I_{\text{SD}} = 13\text{A}, V_{\text{GS}} = 0\text{V}$	--	--	1.4	V
Reverse Recovery Time	$t_{\text{rr}}$	$V_{\text{GS}} = 0\text{V}, I_S = 13\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$	--	300	--	ns
Reverse Recovery Charge	$Q_{\text{rr}}$		--	2.0	--	$\mu\text{C}$

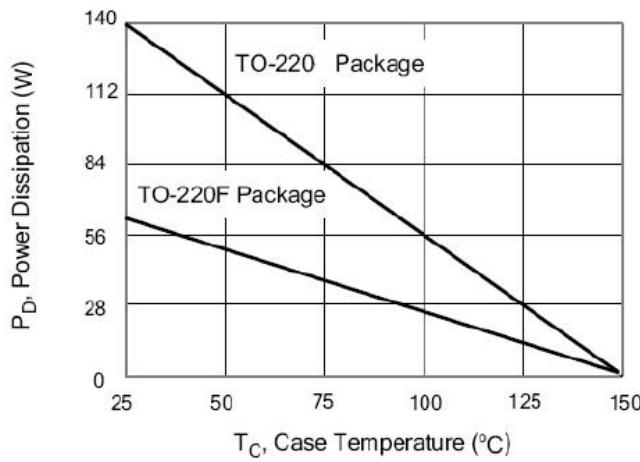
**Notes**

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $V_{\text{DD}} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 1\%$

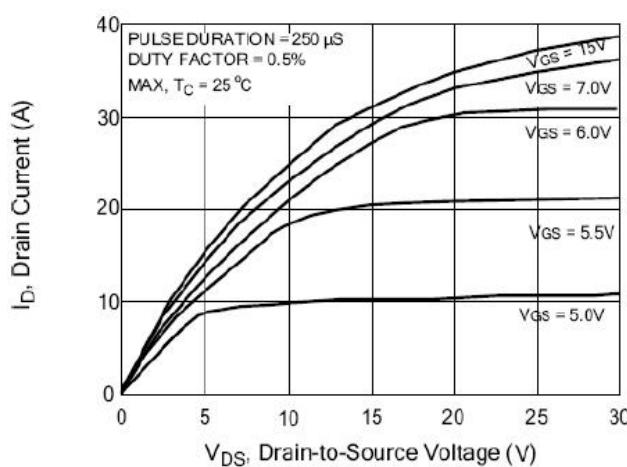
**Typical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted



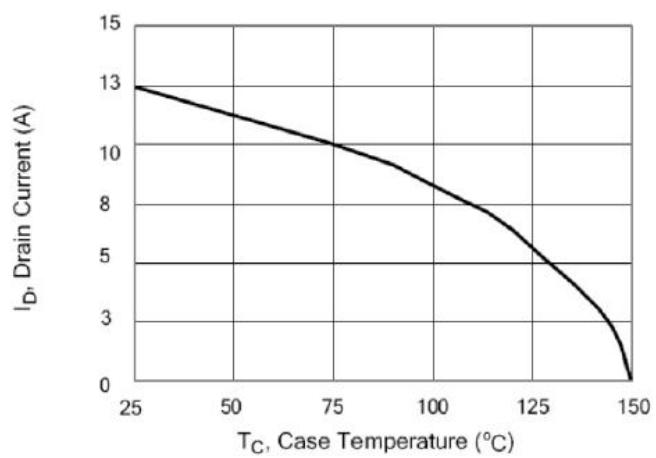
**Figure 2. Maximum Power Dissipation vs Case Temperature**



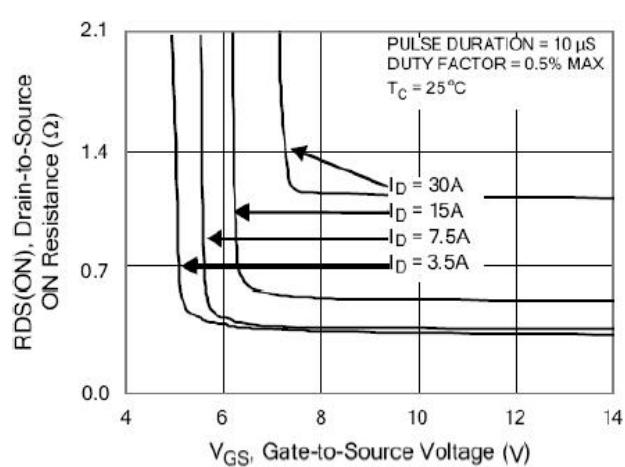
**Figure 4. Typical Output Characteristics**



**Figure 3. Maximum Continuous Drain Current vs Case Temperature**



**Figure 5. Typical Drain-to-Source ON Resistance vs Gate Voltage and Drain Current**



**Typical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

Figure 6. Maximum Peak Current Capability

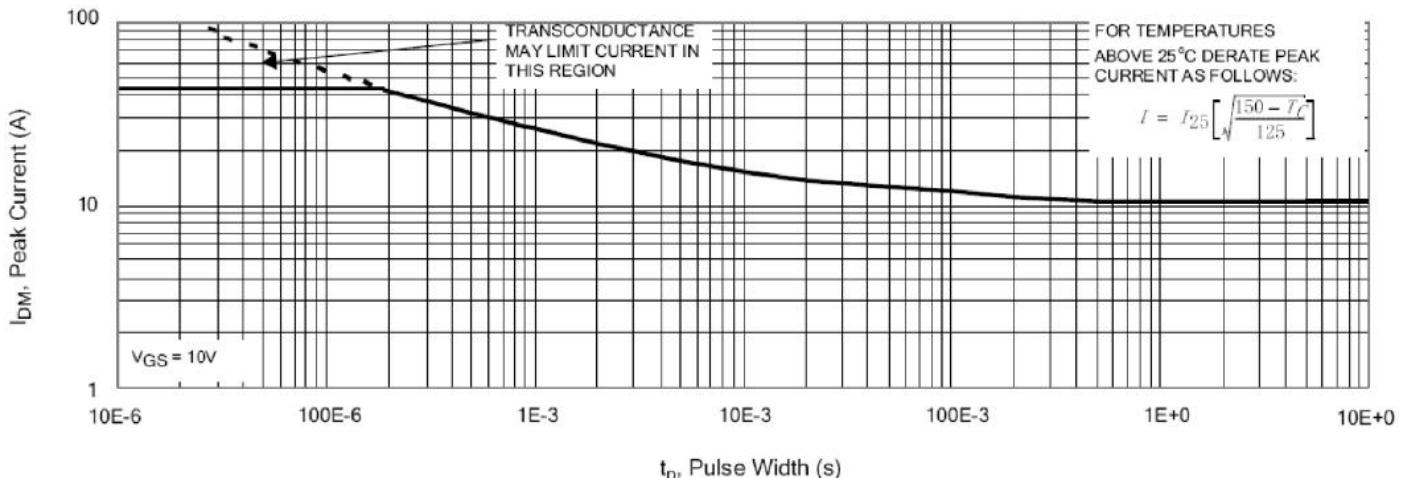


Figure 7. Typical Transfer Characteristics

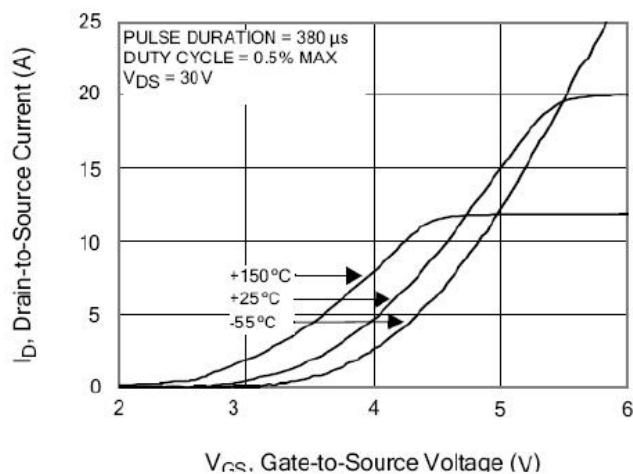


Figure 9. Typical Drain-to-Source ON Resistance vs Drain Current

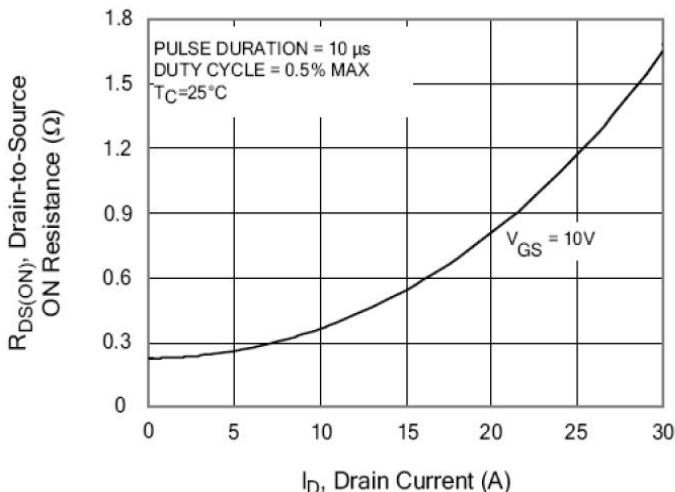


Figure 8. Undclamped Inductive Switching Capability

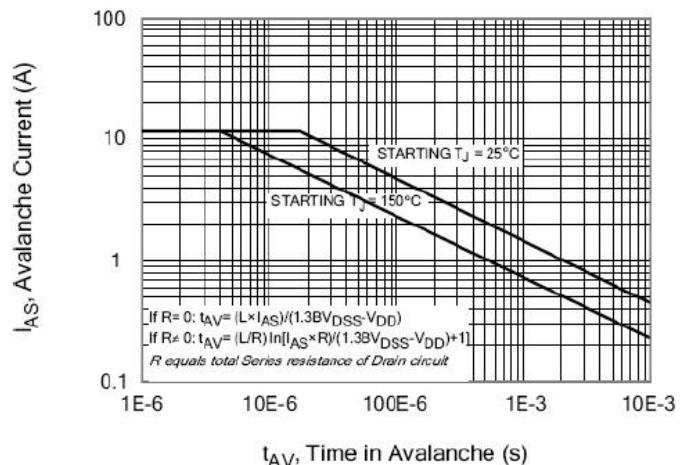
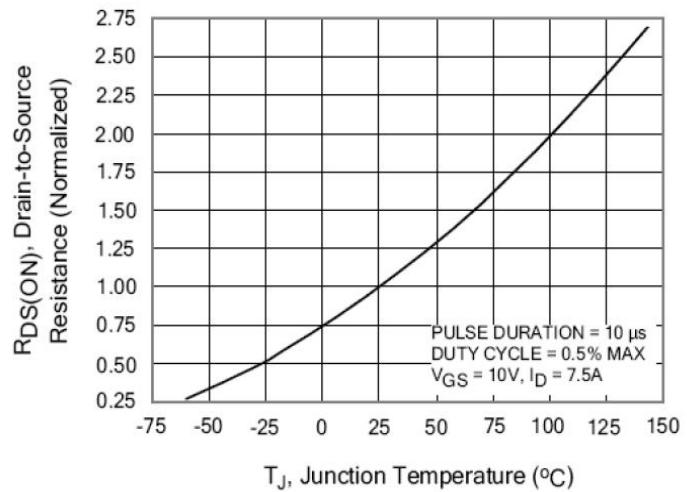


Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature



**Typical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

Figure 11. Typical Breakdown Voltage vs Junction Temperature

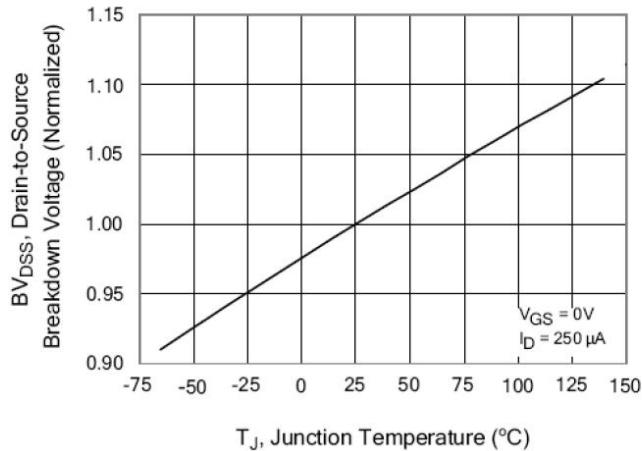


Figure 12. Typical Threshold Voltage vs Junction Temperature

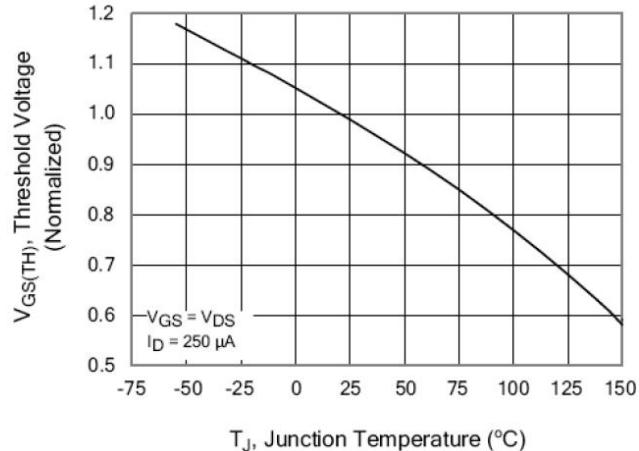


Figure 13. Maximum Forward Bias Safe Operating Area

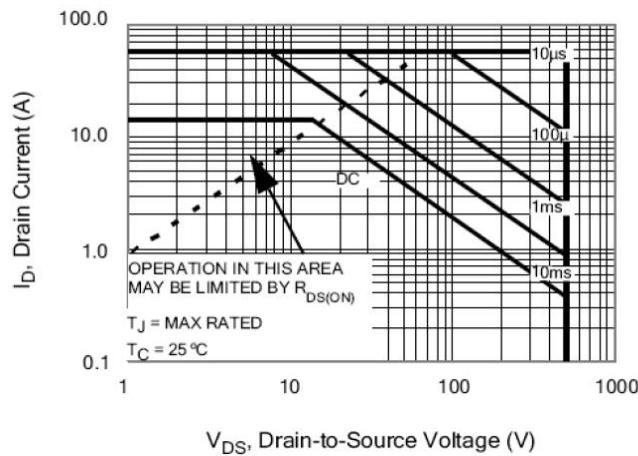


Figure 14. Typical Capacitance vs Drain-to-Source Voltage

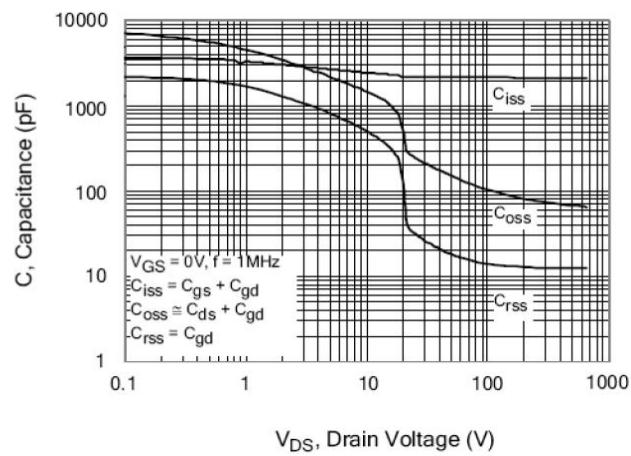


Figure 15. Typical Gate Charge vs Gate-to-Source Voltage

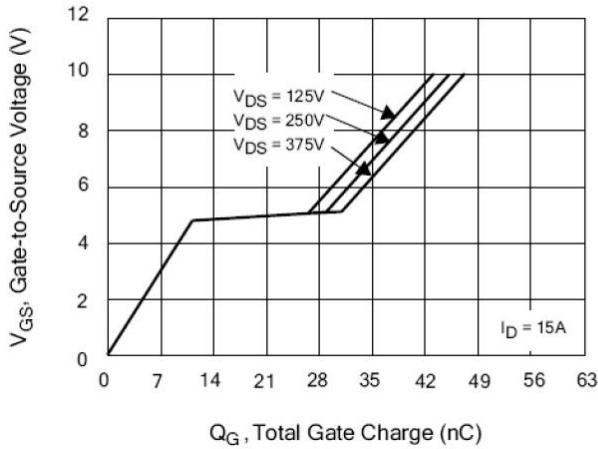
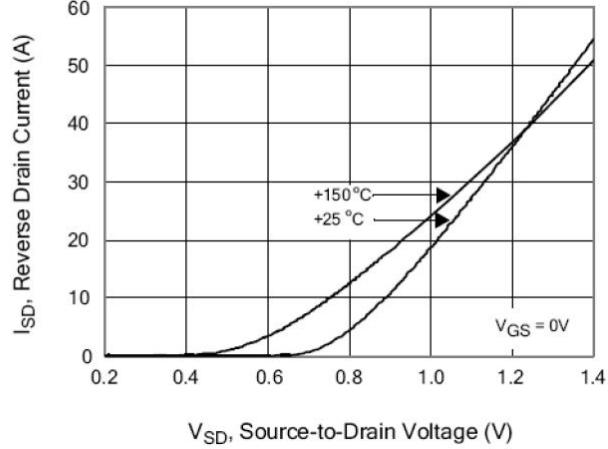
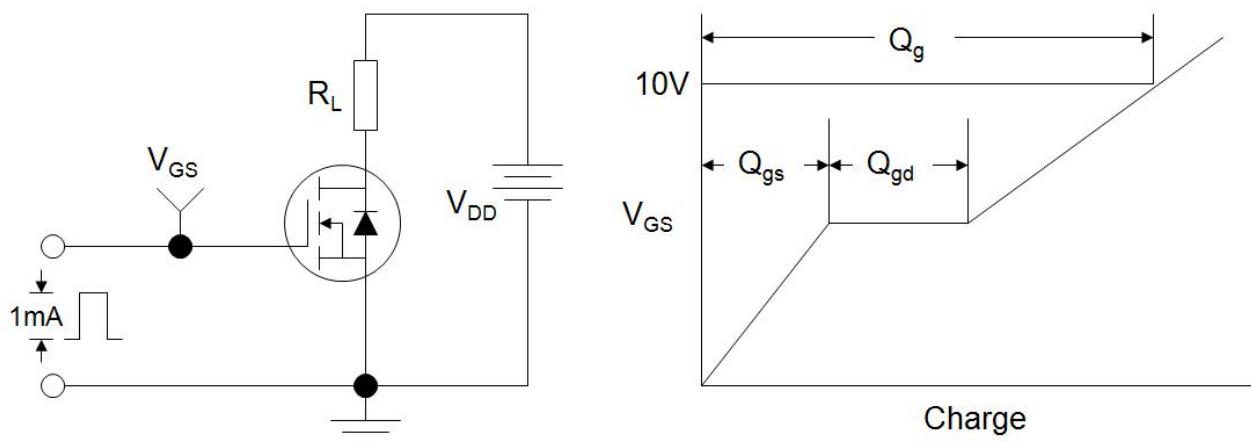
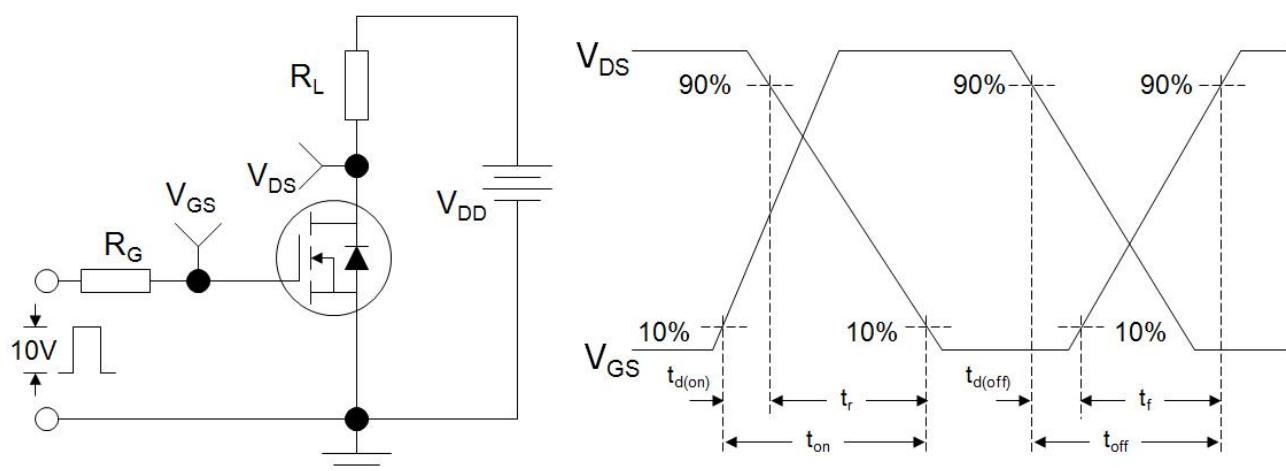


Figure 16. Typical Body Diode Transfer Characteristics



**TEST CIRCUITS AND WAVEFORMS****Figure A: Gate Charge Test Circuit and Waveform****Figure B: Resistive Switching Test Circuit and Waveform****Figure C: Unclamped Inductive Switching Test Circuit and Waveform**